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United States Patent [19]

Kamata et al.

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[45] **Date of Patent: **Sep. 16, 1997**

[54] **WAFER PROBER**

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[73] Assignee: **Tokyo Electron Limited**, Tokyo-To, Japan

[**] Term: **14 Years**

[21] Appl. No.: **53,608**

[22] Filed: **Apr. 25, 1996**

[51] **LOC (6) Cl.** **10-04**

[52] **U.S. Cl.** **D10/75**

[58] **Field of Search** D10/46, 75; 269/13, 269/14, 20, 21, 296, 903; 324/158.1, 754, 762, 761

[56] **References Cited**

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[57] **CLAIM**

The ornamental design for wafer prober, as shown.

DESCRIPTION

FIG. 1 is a top/front/left side perspective view of a wafer prober showing our new design;

FIG. 2 is a top/front/left side perspective view thereof with a front cover open;

FIG. 3 is a front view thereof;

FIG. 4 is a top view thereof;

FIG. 5 is a right side view thereof;

FIG. 6 is a back view thereof;

FIG. 7 is a left side view thereof; and,

FIG. 8 is a bottom view thereof.

1 Claim, 4 Drawing Sheets

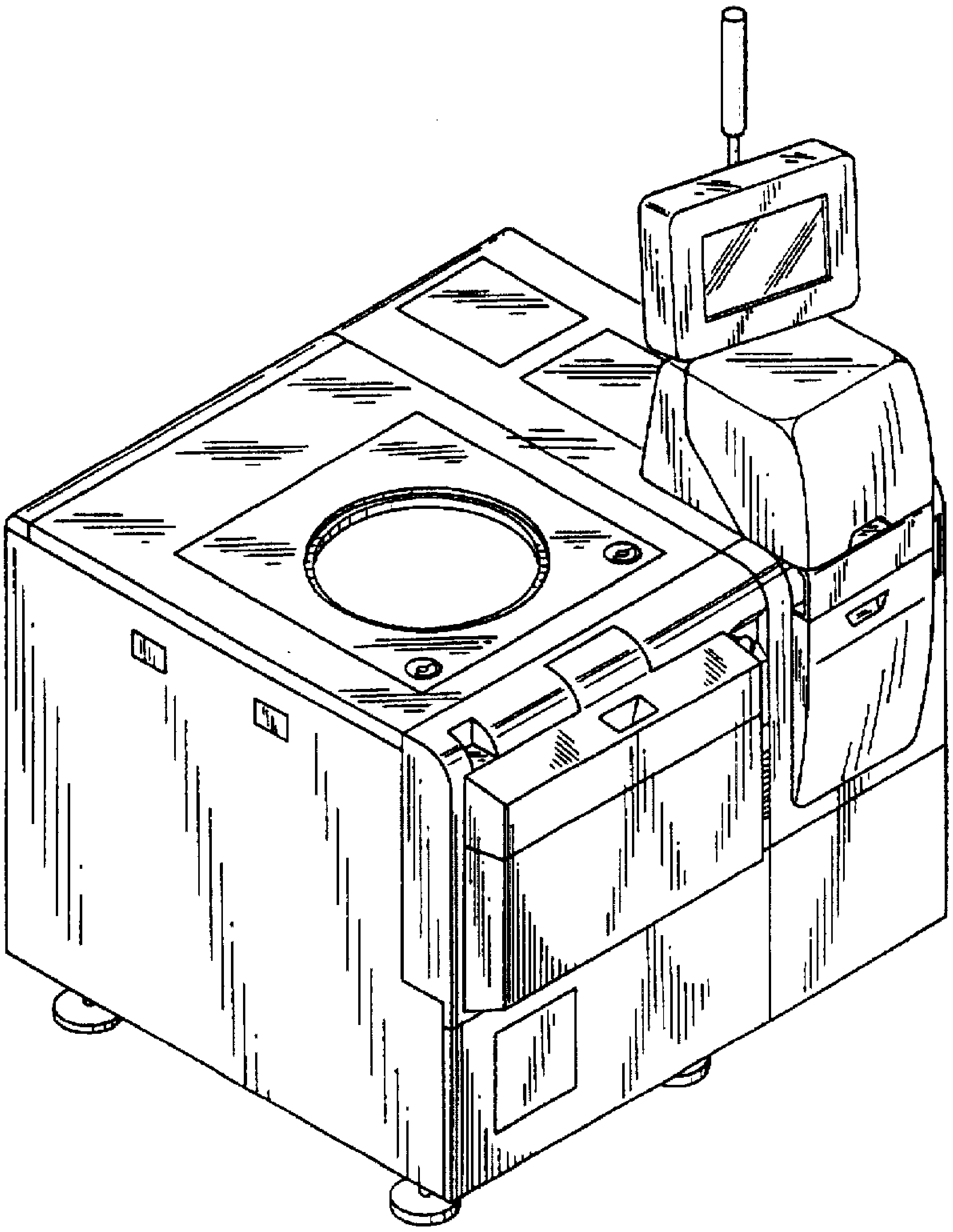

FIG. 1

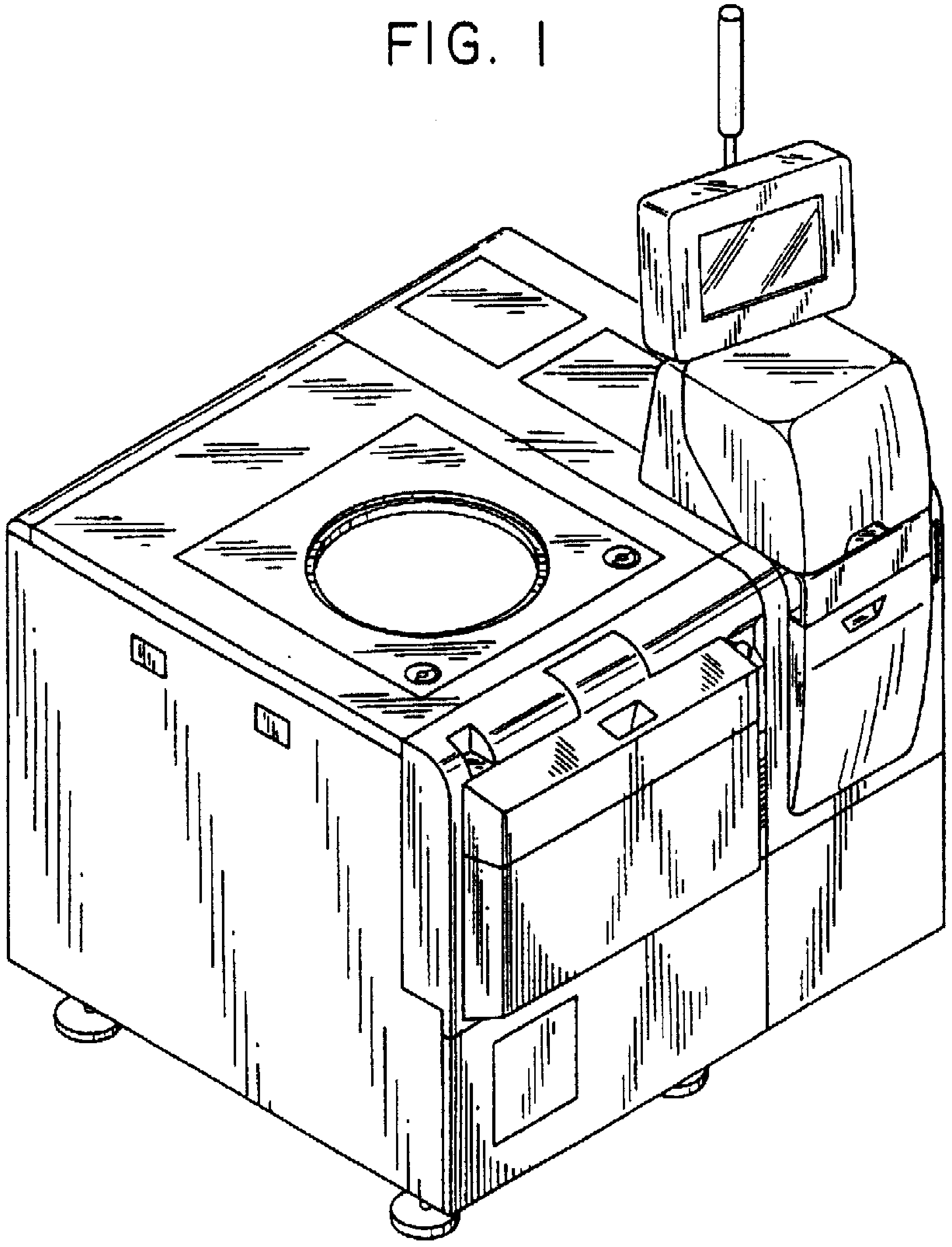

FIG. 2

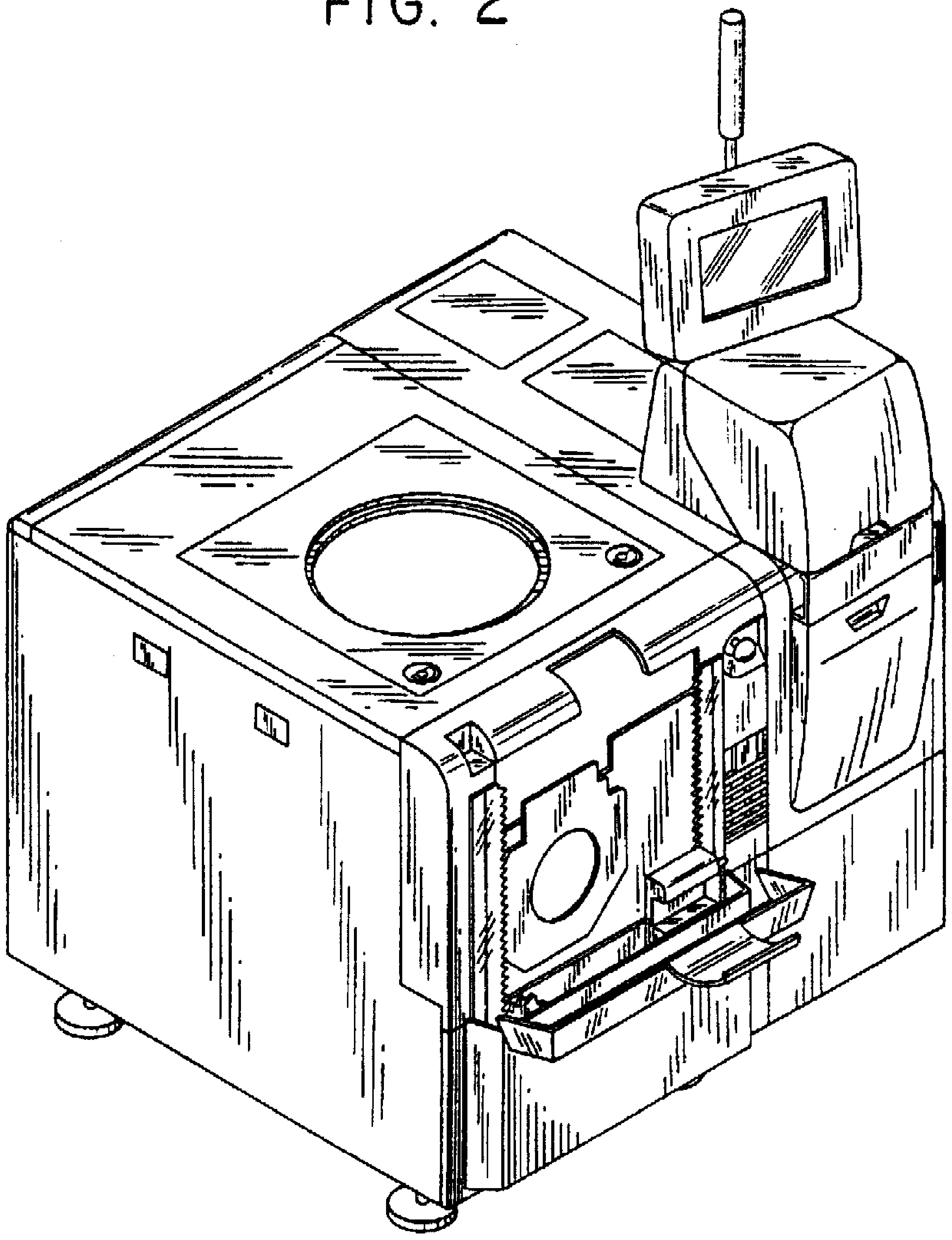

FIG. 3

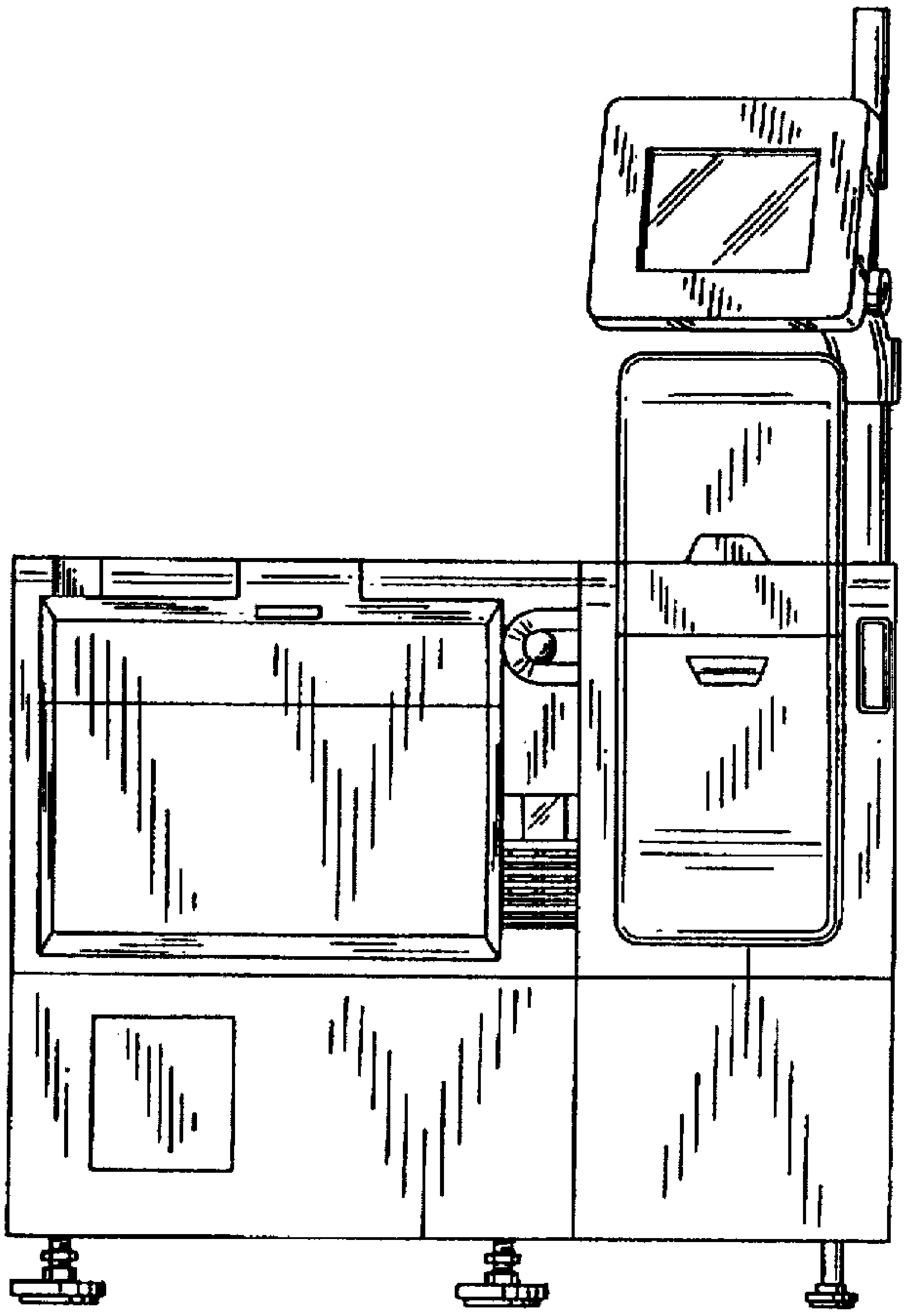

FIG. 4

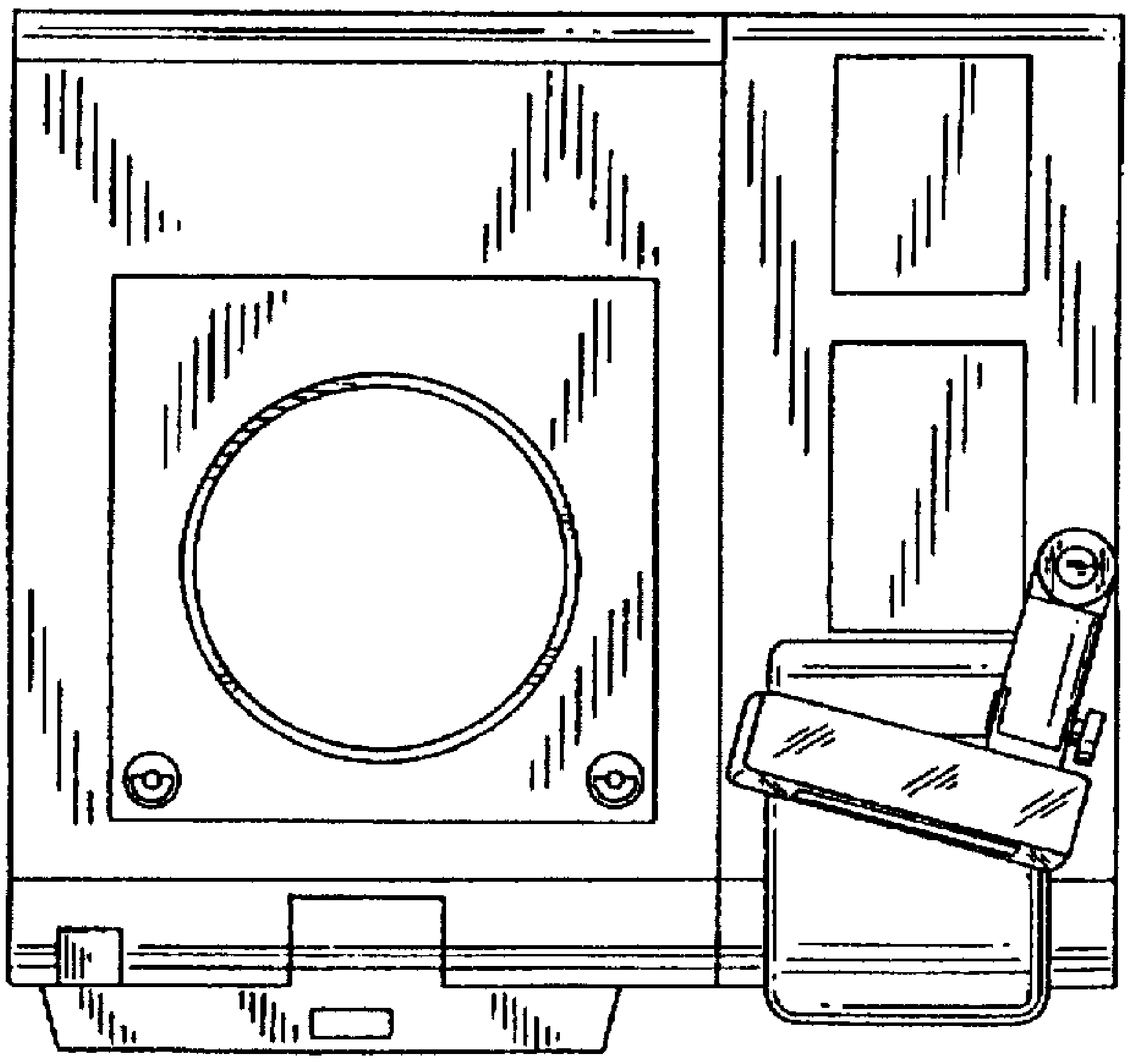

FIG. 5

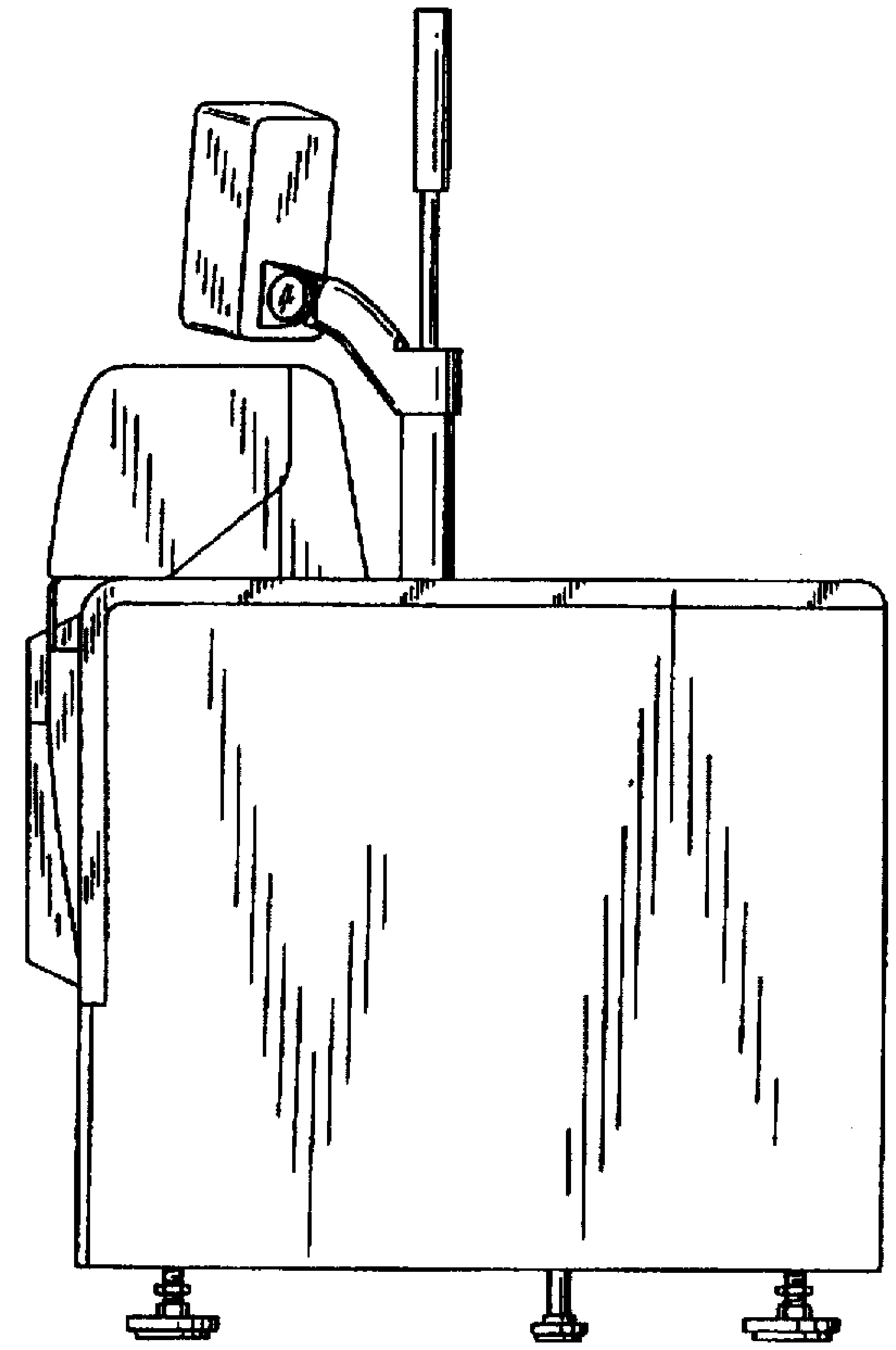

FIG. 6

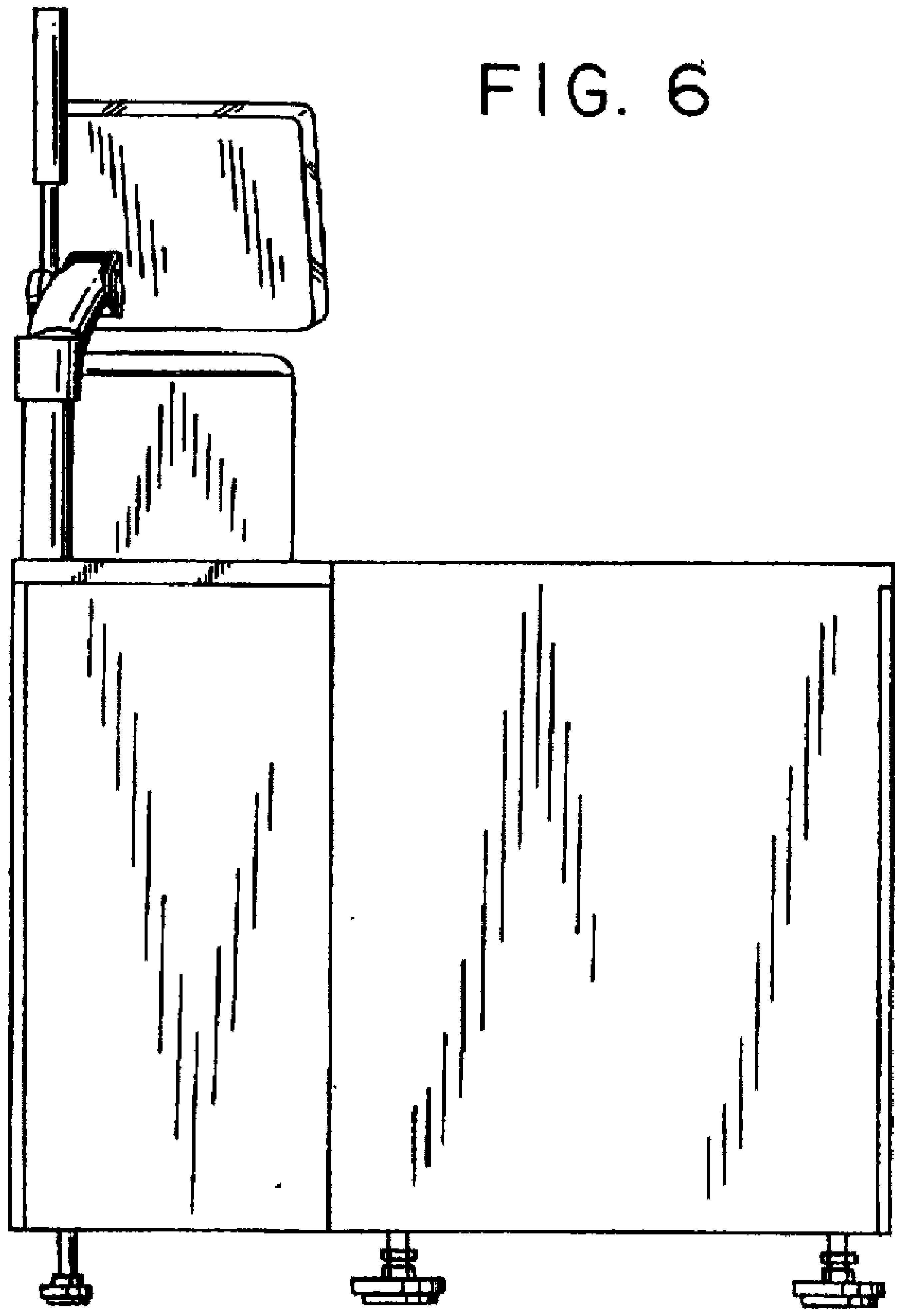

FIG. 7

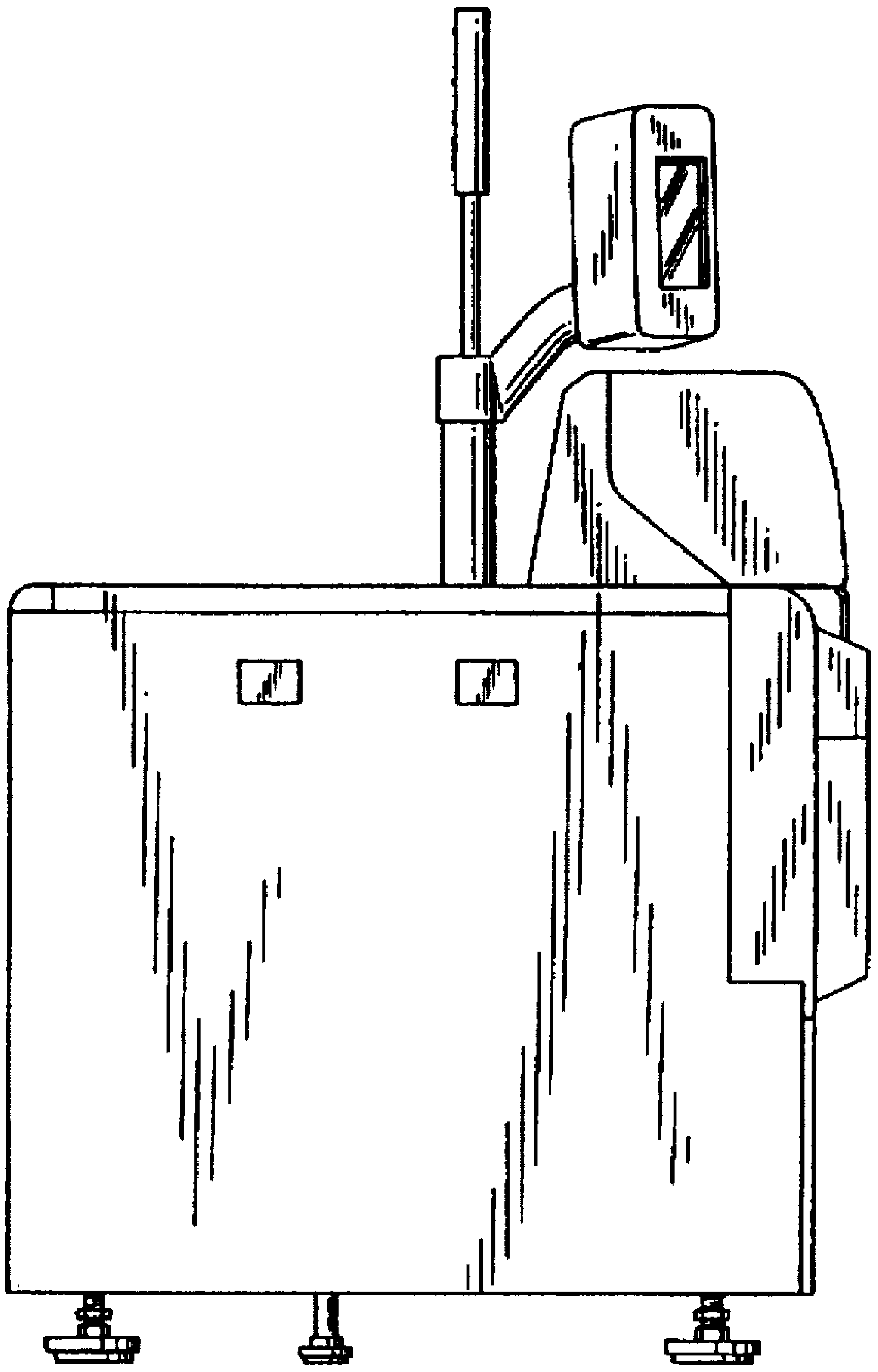

FIG. 8